Application/Control No. Applicant(s)/Patent Under Reexemination TAKEUCHI ET AL. Examiner Shean C Wu Applicant(s)/Patent Under Reexemination TAKEUCHI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

[*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
		Α	US-6,468,607	10-2002	Takehara et al.	428/1.1
		В	US-			
		С	US-			
11		D	US-			
		Ε	US-			
		F_	US-			
5						
			US-			
		1	US-			
		J	US-			
		K	US-			
		L	US-			
		М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т			<u> </u>		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.